

Supporting information

**Crystallization and Conformation Engineering of Solution-process Polymer
Transparent Electrodes with High Conductivity**

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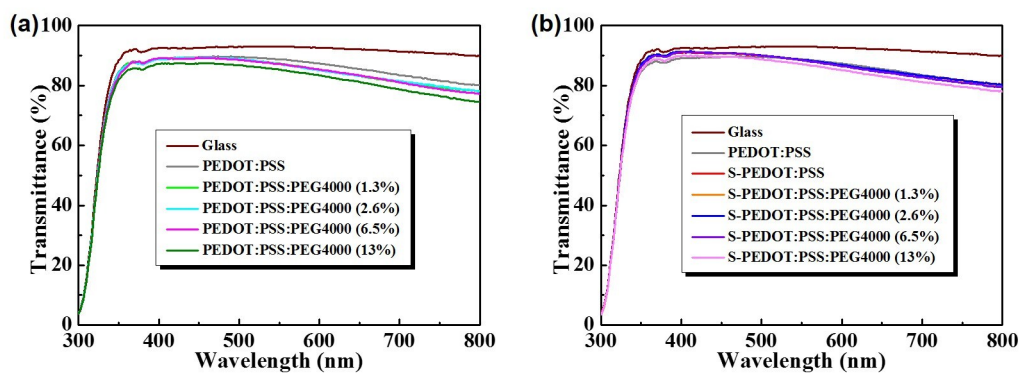


Figure S1. (a) The transmittance spectra of glass, pristine PEDOT:PSS and modified PEDOT:PSS by polyethylene glycol 4000 (PEG4000) with various weight ratios in the range from 300 nm to 800 nm. (b) The transmittance spectra of glass, pristine PEDOT:PSS, H₂SO₄-treated PEDOT:PSS (S-PEDOT:PSS), S-PEDOT:PSS (~40 nm) with various weight ratios of PEG4000 in the range from 300 nm to 800 nm.

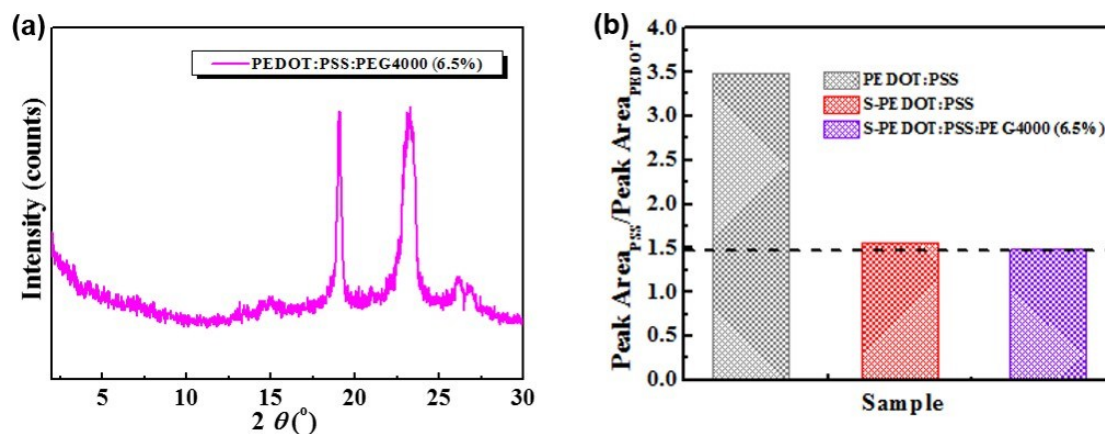


Figure S2. X-ray diffraction (XRD) pattern of PEDOT:PSS with 6.5 wt% PEG4000 (PEDOT:PSS:PEG4000 (6.5%)) in the range from 2° to 30°. (b) The peak area ratios of PSS to PEDOT of pristine PEDOT:PSS, S-PEDOT:PSS and H₂SO₄-treated PEDOT:PSS with 6.5 wt% PEG4000 (S-PEDOT:PSS:PEG4000 (6.5%)) in X-ray photoelectron spectroscopy (XPS) S(2p) spectra by XPS peak processing.

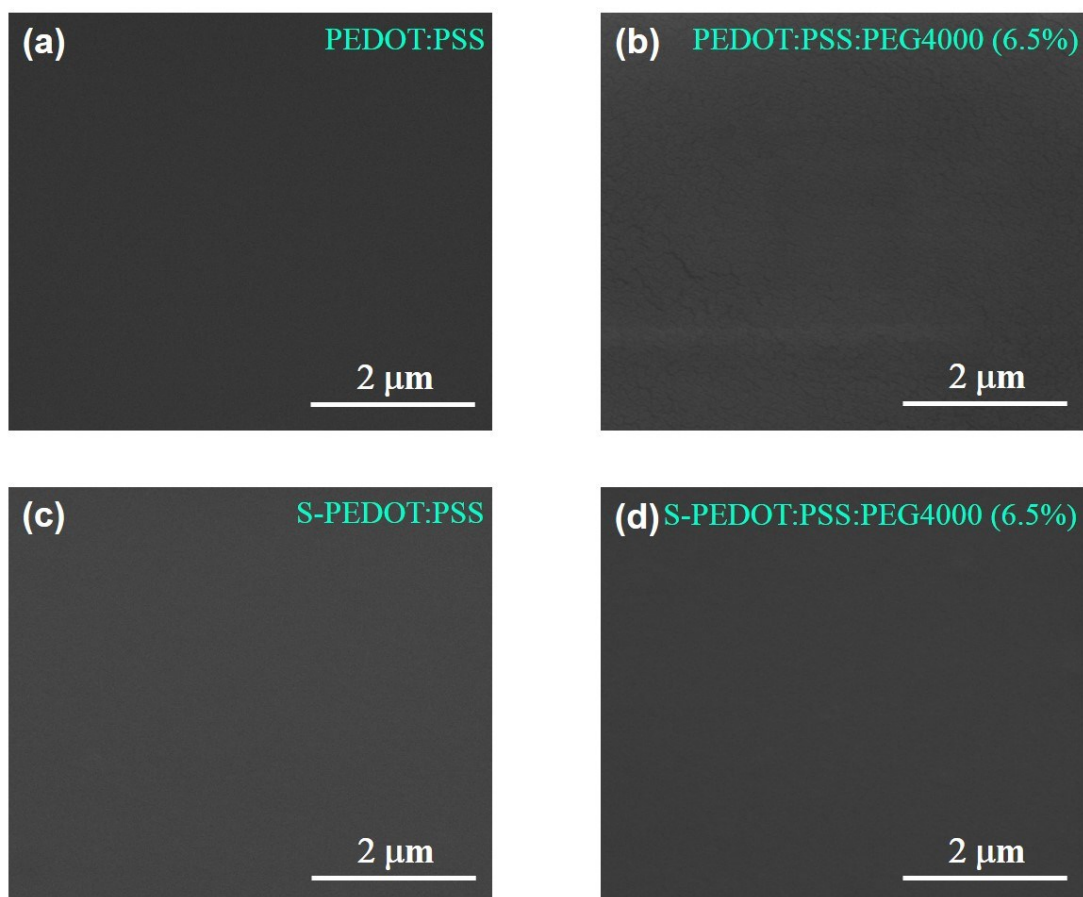


Figure S3. Low-magnification scanning electron microscopy (SEM) images of (a) pristine PEDOT:PSS, (b) PEDOT:PSS:PEG4000 (6.5%), (c) S-PEDOT:PSS and (d) S-PEDOT:PSS:PEG4000 (6.5%).

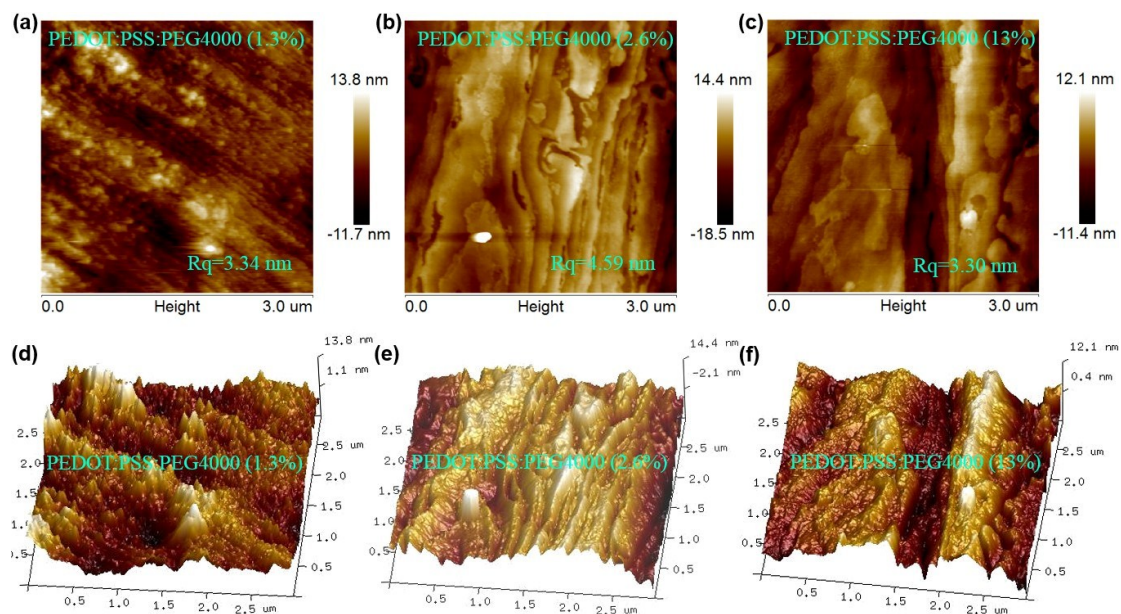


Figure S4. Atomic force microscope (AFM) height images of (a) PEDOT:PSS:PEG4000 (1.3%), (b) PEDOT:PSS:PEG4000 (2.6%), (c) PEDOT:PSS:PEG4000 (13%) and the corresponding three-dimensional images of (d) PEDOT:PSS:PEG4000 (1.3%), (e) PEDOT:PSS:PEG4000 (2.6%), (f) PEDOT:PSS:PEG4000 (13%), respectively.

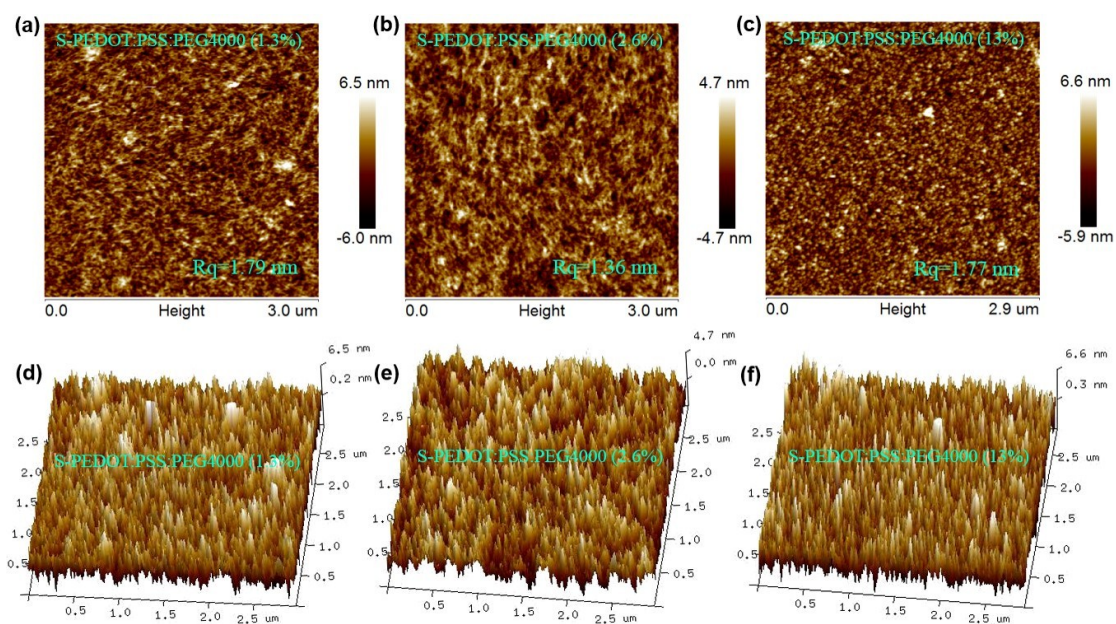


Figure S5. AFM height images of (a) S-PEDOT:PSS:PEG4000 (1.3%), (b) S-PEDOT:PSS:PEG4000 (2.6%), (c) S-PEDOT:PSS:PEG4000 (13%) and the corresponding three-dimensional images of (d) S-PEDOT:PSS:PEG4000 (1.3%), (e) S-PEDOT:PSS:PEG4000 (2.6%), (f) S-PEDOT:PSS:PEG4000 (13%), respectively.

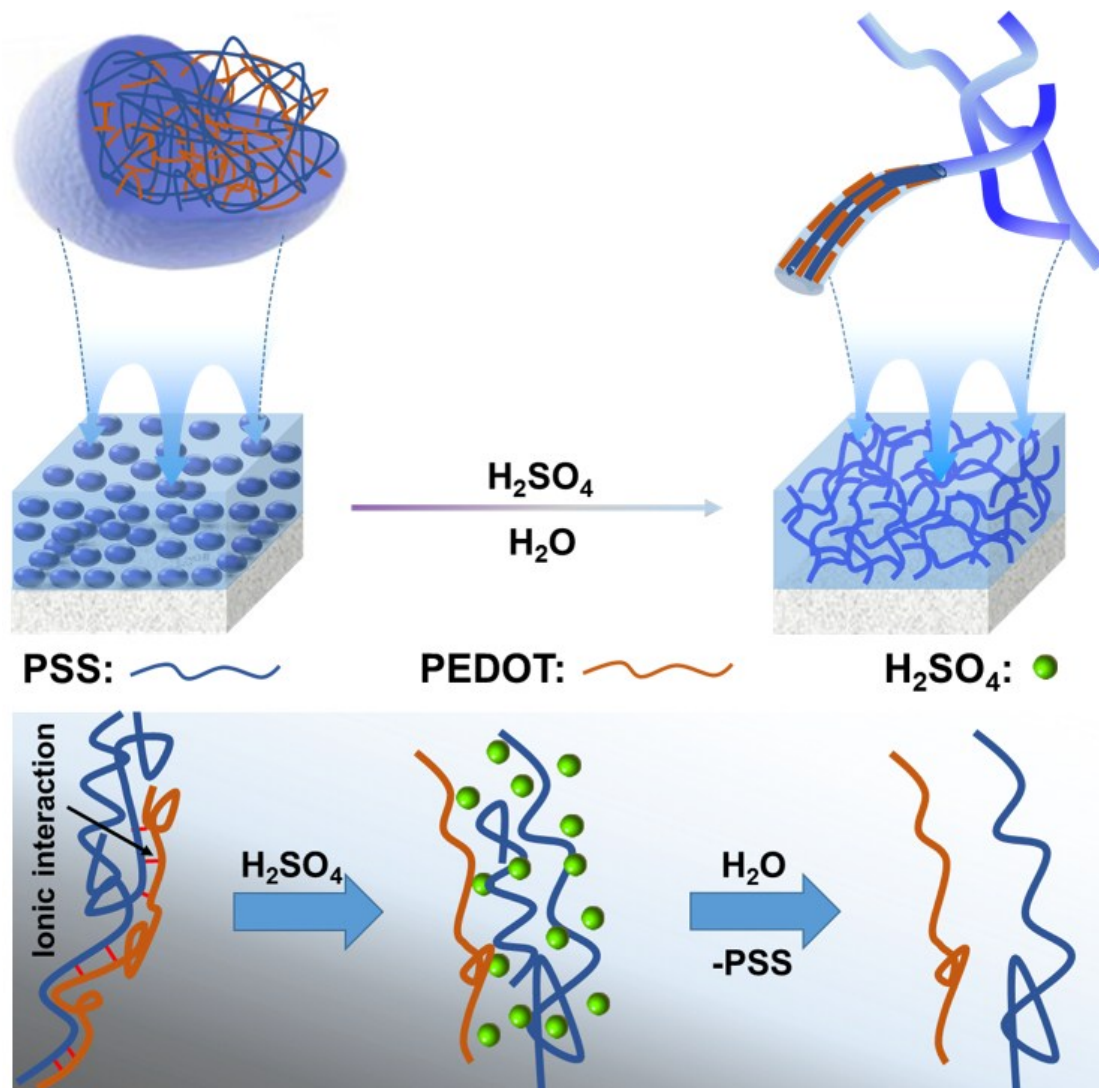


Figure S6. The schematic diagram of the configuration change of PEDOT:PSS during the treatment of H_2SO_4 , as well as the simplified mechanism diagram.

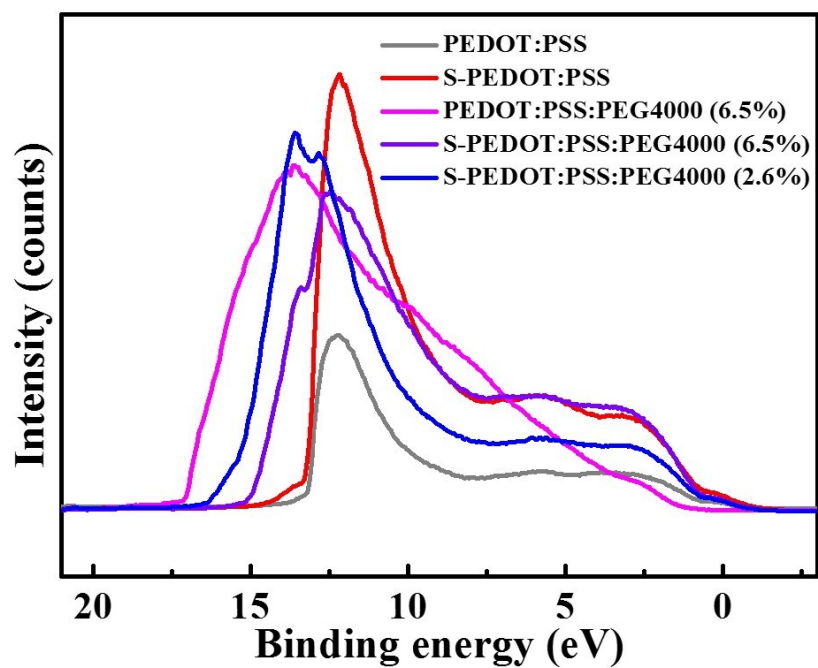


Figure S7. Ultraviolet photoelectron spectroscopy (UPS) spectra of PEDOT:PSS, S-PEDOT:PSS, PEDOT:PSS:PEG4000 (6.5%), S-PEDOT:PSS:PEG4000 (2.6%) and S-PEDOT:PSS:PEG4000 (6.5%).

Table S1. The work functions estimated via kelvin probe force microscope (KPFM) of gold (Au), PEDOT:PSS, S-PEDOT:PSS, PEDOT:PSS:PEG4000 (6.5%) and S-PEDOT:PSS:PEG4000 (6.5%), respectively.

Transparent electrode	Au	PEDOT:PSS	S-PEDOT:PSS	PEDOT:PSS: PEG4000 (6.5%)	S- PEDOT:PSS:PE G4000 (6.5%)
Work function (eV)	-5.1000	-4.8340	-4.7330	-4.1420	-4.5760

We select gold as the reference standard to estimate the work functions of the pristine and hybrid PEDOT:PSS films under the same conditions. The potential of the probe is -4.2650 eV.

Table S2. The work functions estimated by ultraviolet photoelectron spectroscopy (UPS) of PEDOT:PSS, S-PEDOT:PSS, PEDOT:PSS:PEG4000 (6.5%), S-PEDOT:PSS:PEG4000 (2.6%) and S-PEDOT:PSS:PEG4000 (6.5%), respectively.

Transparent electrode	PEDOT:PSS	S-PEDOT:PSS	PEDOT:PSS: PEG4000 (6.5%)	S- PEDOT:PSS:P EG4000 (2.6%)	S- PEDOT:PSS:P EG4000 (6.5%)
Work function (eV)	-5.5	-5.1	-3.6	-3.8	-3.7

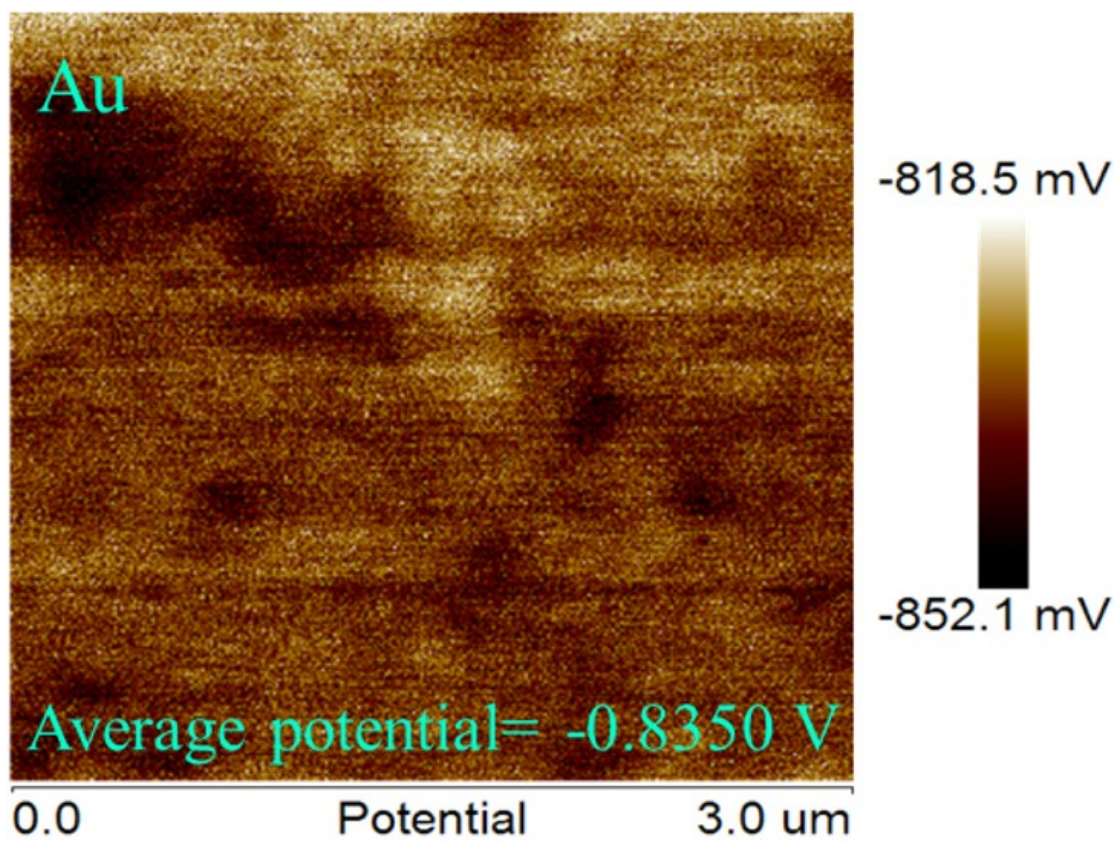


Figure S8. Kelvin probe force microscope (KPFM) image of gold (Au).

Table S3. Device parameters of the inverted structure based on glass substrate/cathode/zinc oxide (ZnO)/active layer/molybdenum trioxide (MoO₃)/silver (Ag).

Cathode	Active layer	J_{sc} (mA cm ⁻²)	V_{oc} (V)	FF (%)	PCE (%)
PEDOT:PSS	P3HT:PC ₆₁ BM	2.788	0.592	45.7	0.8(1.0) ^a
S-PEDOT:PSS	P3HT:PC ₆₁ BM	8.318	0.558	43.4	2.0(2.3) ^a
S-PEDOT:PSS:PEG4000 (2.6%)	P3HT:PC ₆₁ BM	8.359	0.610	51.8	2.6(2.8) ^a
S-PEDOT:PSS:PEG4000 (6.5%)	P3HT:PC ₆₁ BM	9.003	0.620	57.0	3.2(3.3) ^a
S-PEDOT:PSS:PEG4000 (13%)	P3HT:PC ₆₁ BM	7.938	0.613	53.3	2.6(2.7) ^a
ITO	P3HT:PC ₆₁ BM	8.120	0.604	60.0	2.9(3.1) ^a
S-PEDOT:PSS	PTB7: PC ₇₁ BM	9.354	0.715	64.7	4.3(4.6) ^a
S-PEDOT:PSS:PEG4000 (6.5%)	PTB7: PC ₇₁ BM	15.880	0.744	68.6	8.1(8.3) ^a
ITO	PTB7: PC ₇₁ BM	13.045	0.726	66.5	6.3(6.5) ^a

a: The best PCE. Each cell had the effective area of 0.15 cm².

Table S4. Device parameters of the conventional structure based on glass substrate/anode/PEDOT:PSS Al 4083/active layer/lithium fluoride (LiF)/aluminum (Al).

Anode	Active layer	J_{sc} (mA cm ⁻²)	V_{oc} (V)	FF (%)	PCE (%)
PEDOT:PSS	P3HT:PC ₆₁ BM	7.114	0.500	38.7	1.4(1.6) ^a
S-PEDOT:PSS	P3HT:PC ₆₁ BM	7.747	0.521	46.8	1.9(2.2) ^a
S-PEDOT:PSS:PEG4000 (2.6%)	P3HT:PC ₆₁ BM	8.255	0.537	48.6	2.2(2.6) ^a
S-PEDOT:PSS:PEG4000 (6.5%)	P3HT:PC ₆₁ BM	8.720	0.590	49.7	2.6(2.9) ^a
S-PEDOT:PSS:PEG4000 (13%)	P3HT:PC ₆₁ BM	7.300	0.584	48.5	2.1(2.3) ^a
ITO	P3HT:PC ₆₁ BM	8.353	0.610	60.5	3.1(3.5) ^a
S-PEDOT:PSS	PTB7: PC ₇₁ BM	12.745	0.732	67.3	6.3(6.6) ^a
S-PEDOT:PSS:PEG4000 (6.5%)	PTB7: PC ₇₁ BM	13.949	0.744	63.4	6.6(6.8) ^a
ITO	PTB7: PC ₇₁ BM	14.267	0.738	69.3	7.3(7.6) ^a

a: The best PCE. Each cell had the effective area of 0.15 cm².

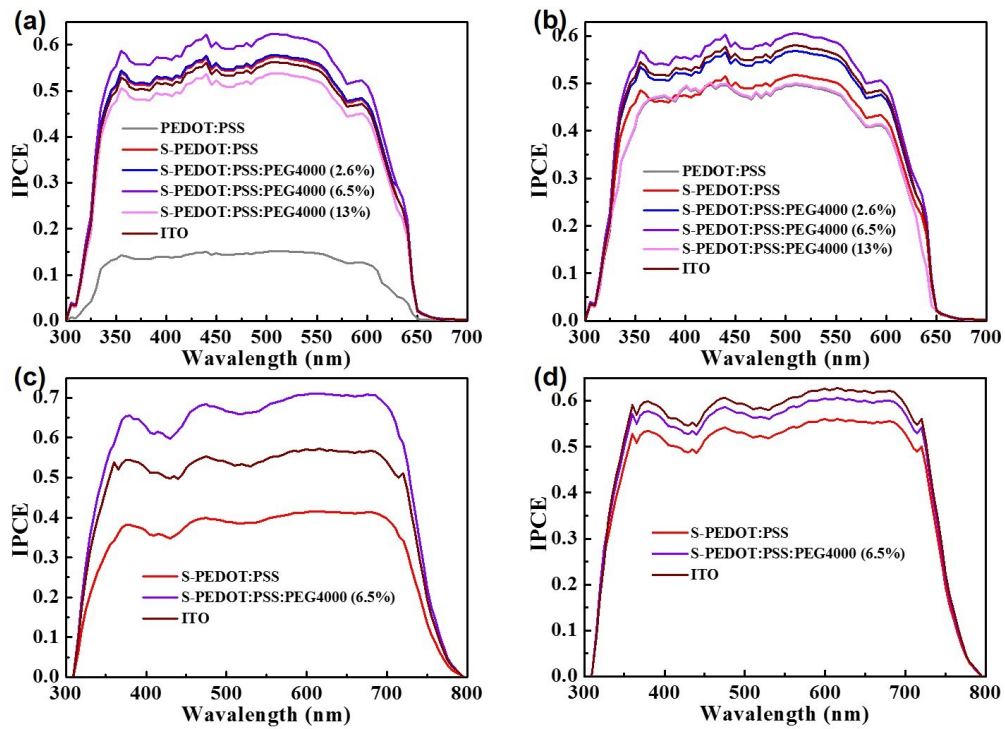


Figure S9. Incident photon to current conversion efficiency (IPCE) spectra of (a, c) based on the same inverted structure device with the active layer of P3HT:PC₆₁BM and PTB7:PC₇₁BM, respectively. IPCE spectra of (b, d) depended on the same conventional structure device with the active layer of P3HT:PC₆₁BM and P7B7:PC₇₁BM, respectively.